# PH6030L

## N-channel TrenchMOS logic level FET

Rev. 01 — 29 July 2008

**Product data sheet** 

### 1. Product profile

### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

### 1.2 Features and benefits

- Lead-free package
- Logic level compatibile

- Optimized for use in DC-to-DC converters
- Very low switching and conduction losses

### 1.3 Applications

- DC-to-DC convertors
- Notebook computers

- Switched-mode power supplies
- Voltage regulators

### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	30	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	76.7	Α
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \frac{\text{Figure 11}}{\text{Figure 12}};$	-	3.1	-	nC
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{Figure 10}}; \text{ see}$	-	4.7	6	mΩ



NXP Semiconductors PH6030

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### 2. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1, 2, 3	S	source		_
4	G	gate	mb (	D
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

### 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH6030L	LFPAK	Plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C	-	30	V
$V_{DGR}$	drain-gate voltage	25 °C $\leq$ T <sub>j</sub> $\leq$ 150 °C; R <sub>GS</sub> = 20 k $\Omega$	-	30	V
$V_{GS}$	gate-source voltage		-20	20	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 100 °C; see <u>Figure 1</u>	-	48.5	Α
		$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{see } \frac{\text{Figure 3}}{\text{Figure 3}}};$	-	76.7	Α
I <sub>DM</sub>	peak drain current	$t_p \le 10 \mu s$ ; pulsed; $T_{mb} = 25 \text{ °C}$ ; see Figure 3	-	300	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	62.5	W
T <sub>stg</sub>	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	in diode				
Is	source current	T <sub>mb</sub> = 25 °C	-	52	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	208	Α
Avalanche	ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 31 A; $V_{sup}$ ≤ 30 V; $t_p$ = 0.14 ms; $R_{GS}$ = 50 $\Omega$ ; unclamped inductive load	-	95	mJ

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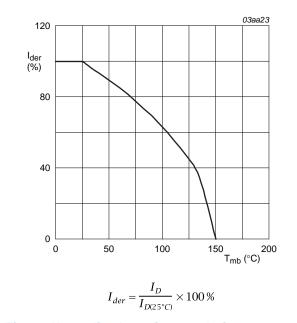


Fig 1. Normalized continuous drain current as a function of mounting base temperature

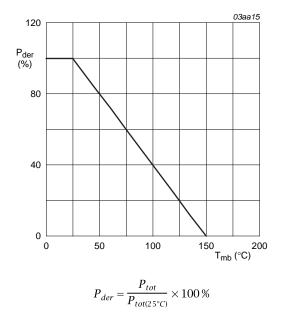


Fig 2. Normalized total power dissipation as a function of mounting base temperature

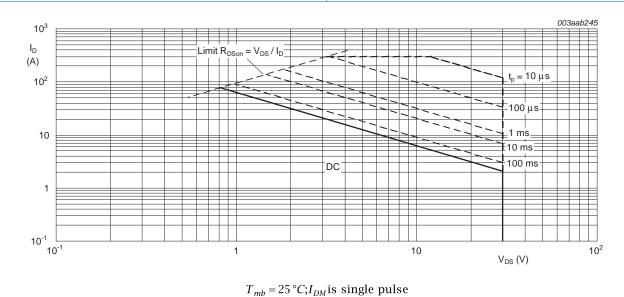


Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

### N-channel TrenchMOS logic level FET

### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W

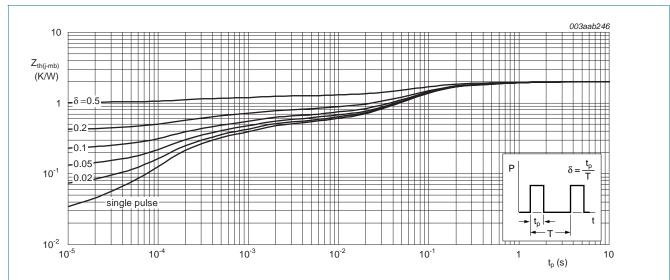


Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration

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### 6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
Static characteristics V <sub>(BR)DSS</sub> drain-source breakdown voltage I <sub>D</sub> = 250 μA; V <sub>GS</sub> = 0 V; T <sub>J</sub> = .55 °C 27 -   V <sub>GS(th)</sub> gate-source threshold voltage I <sub>D</sub> = 250 μA; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 25 °C; see Figure 7 30 -   V <sub>GS(th)</sub> gate-source threshold voltage I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = .55 °C; see Figure 7 - -   I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = 25 °C; see Figure 7 I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>J</sub> = 25 °C; see Figure 8 1.3 1.3   I <sub>DSS</sub> drain leakage current V <sub>DS</sub> = 30 V; V <sub>GS</sub> = 0 V; T <sub>J</sub> = 25 °C; see Figure 8 - -   I <sub>DSS</sub> gate leakage current V <sub>DS</sub> = 30 V; V <sub>DS</sub> = 0 V; T <sub>J</sub> = 25 °C - -   V <sub>DS</sub> = 30 V; V <sub>DS</sub> = 0 V; T <sub>J</sub> = 25 °C - - -   V <sub>DS</sub> = 30 V; V <sub>DS</sub> = 0 V; T <sub>J</sub> = 25 °C - -   V <sub>DS</sub> = 16 V; V <sub>DS</sub> = 0 V; T <sub>J</sub> = 25 °C - -   V <sub>DS</sub> = 16 V; V <sub>DS</sub> = 0 V; T <sub>J</sub> = 25 °C; see Figure 10 - -   V <sub>DS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>J</sub> = 25 °C; see Figure 10 - -   V <sub>DS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>J</sub> = 25 °C; see Figure 11 - 1.5   Dynamic characteristics - <	-	-	V			
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	V		
$V_{GS(th)}$	-		-	-	2.6	V
			0.8	-	-	V
			1.3	1.7	2.15	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		V <sub>DS</sub> = 30 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 150 °C	-	-	100	μΑ
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 16 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	100	nA
		V <sub>GS</sub> = -16 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	100	nA
$R_{DSon}$		· · · · · · · · · · · · · · · · · ·	-	8.5	10.6	mΩ
		,	-	7.3	9.7	mΩ
		,	-	4.7	6	mΩ
R <sub>G</sub>	gate resistance	f = 1 MHz	-	1.75	-	Ω
Dynamic	characteristics					
$Q_{G(tot)}$	total gate charge		-	15.2	-	nC
			-	14	-	nC
Q <sub>GS</sub>	gate-source charge		-	8.5	-	nC
$Q_{GD}$	gate-drain charge	Figure 12; see Figure 12	-	3.1	-	nC
Q <sub>GS1</sub>	•		-	4.1	-	nC
Q <sub>GS2</sub>	•		-	4.4	-	nC
V <sub>GS(pI)</sub>			-	3.5	-	V
C <sub>iss</sub>	input capacitance		-	2260	-	pF
			-	2540	-	pF
C <sub>oss</sub>	output capacitance		-	460	-	pF
C <sub>rss</sub>	reverse transfer capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 13</u>	-	210	-	pF

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Table 6. Characteristics ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$t_{d(on)}$	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	25	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5.6 \Omega$	-	53	-	ns
$t_{d(off)}$	turn-off delay time		-	27	-	ns
t <sub>f</sub>	fall time		-	14	-	ns
Source-dra	nin diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 14	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S$ = 20 A; $dI_S/dt$ = -100 A/ $\mu$ s; $V_{GS}$ = 0 V; $V_{DS}$ = 30 V	-	34	-	ns
Q <sub>r</sub>	recovered charge	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V}$	-	11.5	-	nC

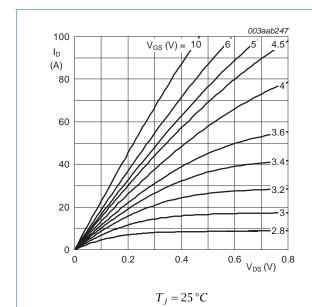


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

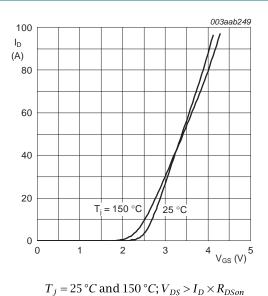
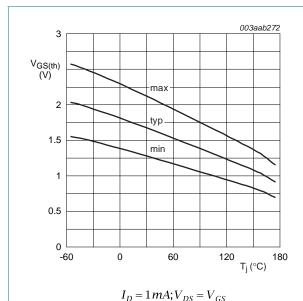


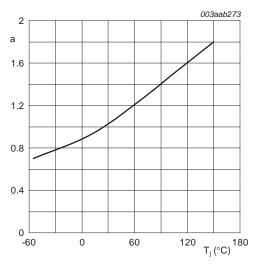
Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

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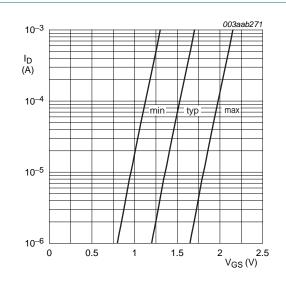
 $I_D - IIIIA$ ,  $V_{DS} - V_{GS}$ 

Fig 7. Gate-source threshold voltage as a function of junction temperature



 $a = \frac{R_{DSon}}{R_{DSon(2.5^{\circ}C)}}$ 

Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature



 $T_i = 25 \,^{\circ}C; V_{DS} = 5 \, V$ 

Fig 8. Sub-threshold drain current as a function of gate-source voltage

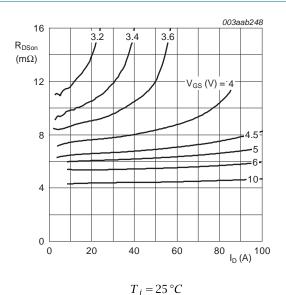


Fig 10. Drain-source on-state resistance as a function of drain current; typical values

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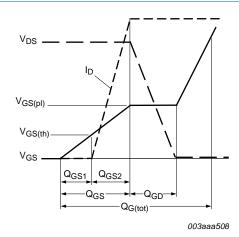


Fig 11. Gate charge waveform definitions

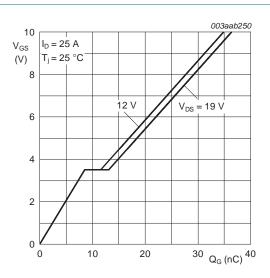


Fig 12. Gate-source voltage as a function of gate charge; typical values

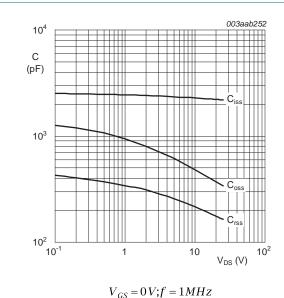
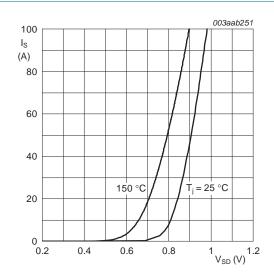


Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



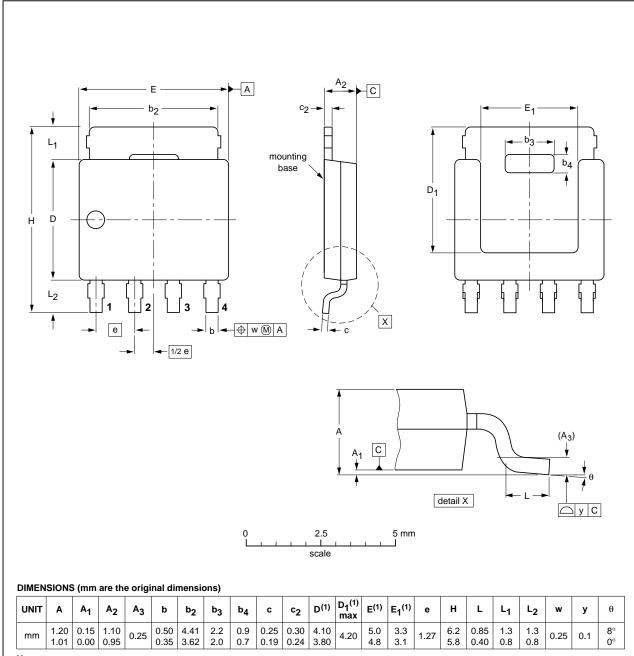
 $T_j = 25 \,{}^{\circ}C$  and  $150 \,{}^{\circ}C$ ;  $V_{GS} = 0 \, V$ 

Fig 14. Source current as a function of source-drain voltage; typical values

### 7. Package outline

#### Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 



#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT669		MO-235			<del>04-10-13</del> 06-03-16	

Fig 15. Package outline SOT669 (LFPAK)

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### 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH6030L_1	20080729	Product data sheet	-	-

#### N-channel TrenchMOS logic level FET

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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